

Notice of References Cited	Application/Control No. 09/608,311	Applicant(s)/Patent Under Reexamination XIANG ET AL.	
	Examiner Paresh Patel	Art Unit 2829	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Scanning Probe Microscopy" by Bottomley et al. (American Chemical Society), Analytical Chemistry, Vol. 68, No. 12, June 15, 1996 (pages 815R to 230R)
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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